

HQ:CSC37/No Al

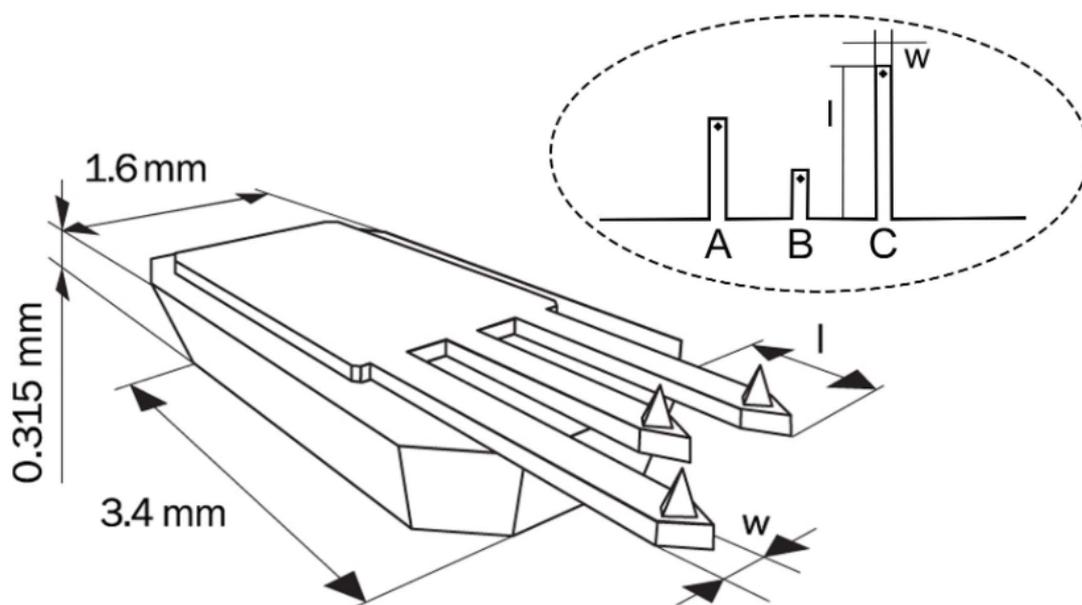
AFM Probe with 3 Different Contact Mode AFM Cantilevers

AFM probes of the HQ:CSC37 series have three different contact mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

Coating

none



AFM Probe Specifications

AFM Tip

| SHAPE | HEIGHT | FULL CONE ANGLE | RADIUS |
|---------|--|-----------------|--------|
| Rotated | 15 μm (12 – 18 μm)* | 40° | < 8 nm |

AFM Cantilever

| CANTILEVER | SHAPE | FORCE CONST. | RES. FREQ. | LENGTH | WIDTH | THICKNESS |
|--------------|-------|-----------------------------|--------------------------|--|---|--|
| Cantilever A | Beam | 0.8 N/m (0.3 – 2 N/m)* | 40 kHz (30 – 55 kHz)* | 250 μm (1 – 255 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever B | Beam | 0.3 N/m (0.1 – 0.6 N/m)* | 20 kHz (15 – 30 kHz)* | 350 μm (1 – 355 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |
| Cantilever C | Beam | 0.4 N/m (0.1 – 1 N/m)* | 30 kHz (20 – 40 kHz)* | 300 μm (1 – 305 μm)* | 35 μm (32 – 38 μm)* | 2 μm (1.5 – 2.5 μm)* |

* typical values